

DM74ALS5245 Octal 3-STATE Transceiver

Features

- Input Hysteresis
- Low output noise generation
- High input noise immunity
- Advanced oxide-isolated, ion implanted Schottky TTL process
- Switching specification guaranteed over the full temperature and V_{CC} range
- PNP inputs to reduce input loading

General Description

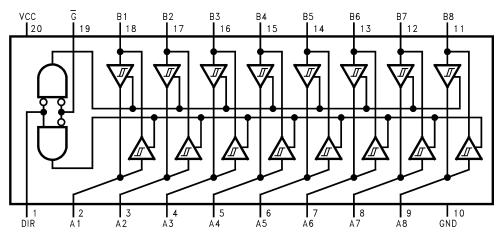
This octal bus transceiver is designed for asynchronous two-way communication between data buses. The inputs include hysteresis which provides improved noise rejection. Data is transmitted either from the A bus to the B bus or from the B bus to the A bus depending on the logic level of the direction control (DIR) input. The device can be disabled via the enable input (\overline{G}) which causes the outputs to enter the high impedance mode so the buses are effectively isolated.

Ordering Information

Order Number	Package Number	Package Description
DM74ALS5245WM	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
DM74ALS5245SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering number.

Connection Diagram



Function Table

Control Inputs		
G	DIR	Operation
L	L	B Data to A Bus
L	Н	A Data to B Bus
Н	Х	High Impedance

L = LOW Logic Level H = HIGH Logic Level X = Don't Care (Either LOW or HIGH Logic Level)

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
V _{CC}	Supply Voltage	7V
VI	Input Voltage	
	Control Inputs	7V
	I/O Ports	5.5V
T _A	Operating Free Air Temperature Range	0°C to +70°C
T _{STG}	Storage Temperature Range	–65°C to +150°C
θ_{JA}	Typical Thermal Resistance	74.0°C/W

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Min.	Max.	Units
V _{CC}	Supply Voltage	4.5	5.5	V
V _{IH}	HIGH Level Input Voltage	2		V
V _{IL}	LOW Level Input Voltage		0.8	V
I _{ОН}	HIGH Level Output Current		-15	mA
I _{OL}	LOW Level Output Current		24	mA
T _A	Free Air Operating Temperature Range	0	70	°C

Electrical Characteristics

Over recommended free air temperature range. All typical values are measured at $V_{CC} = 5V$, $T_A = 25^{\circ}C$.

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
V _{IK}	Input Clamp Voltage	$V_{CC} = Min, I_I = -18mA$				-1.5	V
H _{YS}	Hysteresis (V _{T+} – V _{T–})	$V_{CC} = Min$		0.2	0.32		V
V _{OH}	HIGH Level Output Voltage	$V_{CC} = 4.5 V to$	$V_{CC} = 4.5V$ to 5.5V, $I_{OH} = -0.4$ mA				V
		V _{CC} = Min.	$I_{OH} = -3mA$	2.4	3.2		1
			I _{OH} = Max	2]
V _{OL}	LOW Level Output Voltage	V _{CC} = Min.	I _{OL} = 12mA		0.25	0.4	V
			I _{OL} = 24mA		0.35	0.5	1
I	Input Current at Maximum	V _{CC} = Max.	I/O Ports, V _I = 5.5V			100	μA
	Input Voltage		Control Inputs, V _I = 7V			100	
I _{IH}	HIGH Level Input Current	$V_{CC} = Max., V_I = 2.7V$				20	μA
IIL	LOW Level Input Current	$V_{CC} = Max., V_I = 0.4V$				-100	μA
Ι _Ο	Output Drive Current	$V_{CC} = Max., V_{O} = 2.25V$		-30		-112	mA
I _{CC}	Supply Current	V _{CC} = Max.	Outputs HIGH		30	45	mA
			Outputs LOW		36	55	1
			Outputs Disabled		38	58	1
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	$V_{CC} = 5.0V, T_A = 25^{\circ}C^{(1)}$ (Fig. 1, Fig. 2)			0.5		V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	$V_{CC} = 5.0V, T_A = 25^{\circ}C^{(1)}$ (Fig. 1, Fig. 2)			-0.2		V
V _{IHD}	Minimum High Level Dynamic Input Voltage	$V_{CC} = 5.0V, T_A = 25^{\circ}C^{(2)}$			1.6		V
V _{ILD}	Maximum Low Level Dynamic Input Voltage	$V_{CC} = 5.0V, T_A = 25^{\circ}C^{(2)}$			1.0		V

Notes:

1. n = number of device outputs; n-1 outputs switching, each driven 0V to 3V one output @ GND.

n = number of device outputs; n outputs switching, n–1 inputs switching 0V to 3V. Input under test switching 3V to threshold (V_{ILD}); 0V to threshold (V_{ILD}); f = 1 MHz.

Switching Characteristics

Over recommended operating free air temperature range.

Symbol	Parameter	Conditions	From (Input) To (Output)	Min.	Max.	Units
t _{PLH}	Propagation Delay Time, LOW-to-HIGH Level Output	$V_{CC} = 4.5V$ to 5.5V, $R_1 = R_2 = 500\Omega$,	A or B to B or A	3	10	ns
t _{PHL}	Propagation Delay Time, HIGH-to-LOW Level Output	C _L = 50 pF	A or B to B or A	3	10	ns
t _{PZH}	Output Enable Time to HIGH Level Output		\overline{G} to A or B	5	20	ns
t _{PZL}	Output Enable Time to LOW Level Output		\overline{G} to A or B	5	20	ns
t _{PHZ}	Output Disable Time from HIGH Level Output		G to A or B	2	10	ns
t _{PLZ}	Output Disable Time from LOW Level Output		\overline{G} to A or B	4	15	ns

ALS Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of ALS.

Equipment:

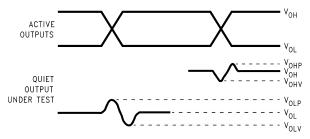
Word Generator

Printed Circuit Board Test Fixture

Dual Trace Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50pF, 500Ω.
- 2. Deskew the word generator so that no two channels have greater than 150ps skew between them. This requires that the oscilloscope be deskewed first. Swap out the channels that have more than 150ps of skew until all channels being used are within 150ps. It is important to deskew the word generator channels before testing. This will ensure that the outputs switch simultaneously.
- 3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- 4. Set V_{CC} to 5.0V.
- Set the word generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and affect the results of the measurement.
- Set the word generator input levels at 0V LOW and 3V HIGH. Verify levels with a digital volt meter.



Notes:

- 3. V_{OHV} and V_{OHP} are measured with respect to V_{OH} reference. V_{OLV} and V_{OLP} are measured with respect to ground reference.
- 4. Input pulses have the following characteristics: f = 1MHz, $t_r = 3ns$, $t_f = 3ns$, skew < 150ps.

Figure 1. Quiet Output Noise Voltage Waveforms

V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV}:

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the HL transition. Measure V_{OHP} and V_{OHV} on the quiet output during the LH transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next decrease the input HIGH voltage level on the word generator, V_{IH} until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

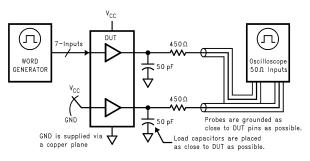
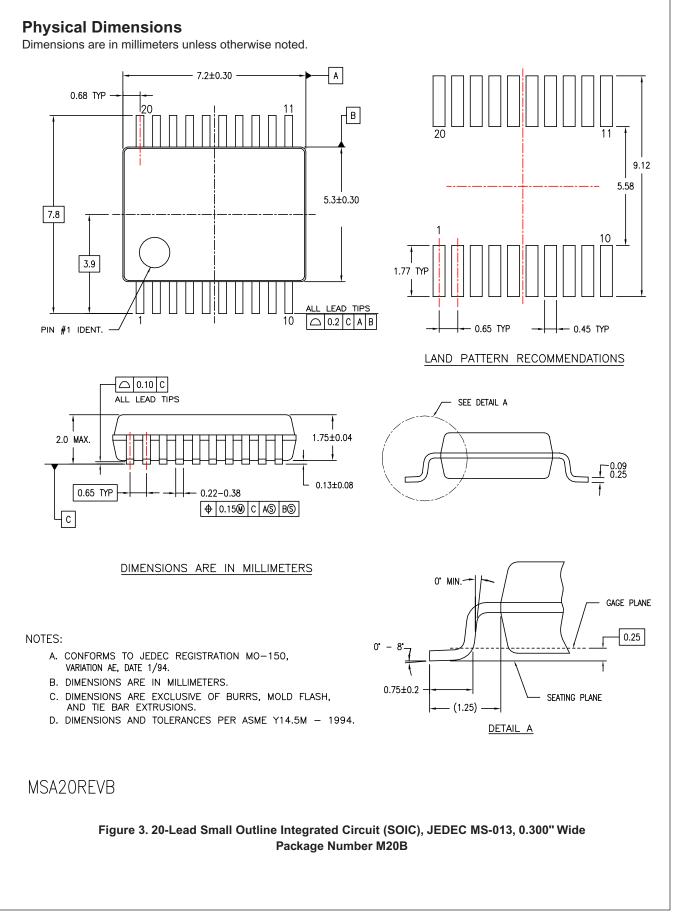
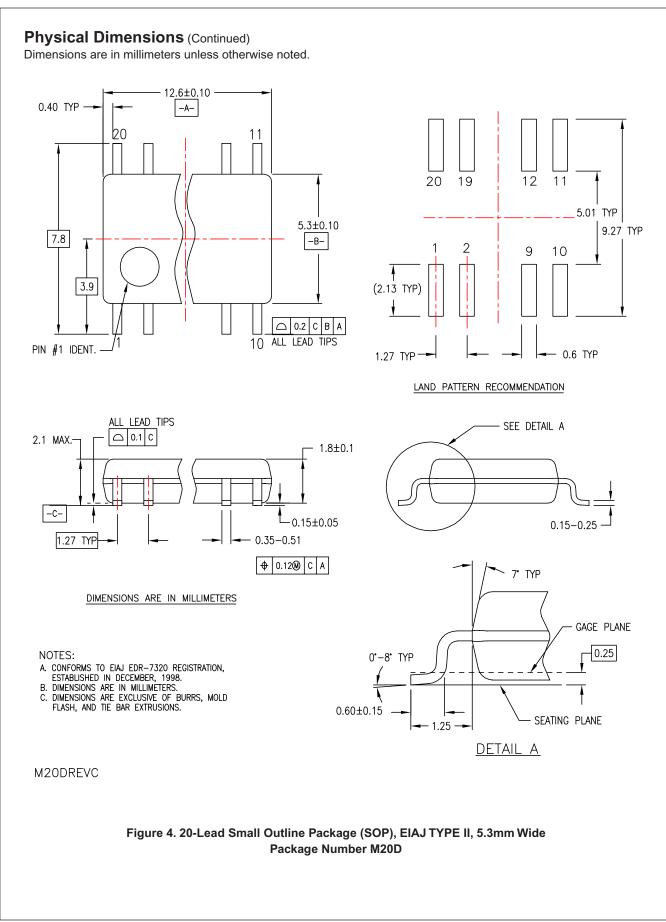


Figure 2. Simultaneous Switching Test Circuit



DM74ALS5245 Octal 3-STATE Transceiver





SEMICONDUCTOR

U

DM74ALS5245 Octal 3-STATE Transceiver

TRADEMARKS

The following are registered and unregistered trademarks and service marks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks

ACEx [®] Build it Now [™] CorePLUS [™] <i>CROSSVOLT</i> [™] CTL [™] Current Transfer Logic [™] EcoSPARK [®] FACT Quiet Series [™] FACT [®] FACT [®] FAST [®] FastvCore [™] FPS [™] FRFET [®] Global Power Resource SM Green FPS [™]	Green FPS™ e-Series™ GTO™ <i>i-Lo</i> ™ IntelliMAX™ ISOPLANAR™ MegaBuck™ MICROCOUPLER™ MicroPak™ Motion-SPM™ OPTOLOGIC® OPTOPLANAR® PDP-SPM™ Power220® Power247® POWEREDGE®	Power-SPM [™] PowerTrench [®] Programmable Active Droop [™] QFT [®] QS [™] QT Optoelectronics [™] Quiet Series [™] RapidConfigure [™] SMART START [™] SMART START [™] SPM [®] STEALTH [™] SuperFET [™] SuperFET [™] SuperSOT [™] -6 SuperSOT [™] -8	SyncFET [™] The Power Franchise [®] TinyBoost [™] TinyBuck [™] TinyLogic [®] TINYOPTO [™] TinyPower [™] TinyPWM [™] TinyWire [™] µSerDes [™] UHC [®] UniFET [™] VCX [™]
--	---	--	--

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.
- A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition		
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.		
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.		
No Identification Needed	n Needed Full Production This datasheet contains final specifications. Fairchild Semiconductor the right to make changes at any time without notice to improve des			
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.		

Rev. 128